

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/848,953	HICKERSON ET AL.	
Examiner	Art Unit	
Sheela C. Chawan	2624	

Sheela C. Chawan

SEARCHED					
Class	Subclass	Date	Examiner		
382	173	10/23/2006	scc		
н	187	10/23/2006	11		
n	292	10/23/2006			
704	232	10/23/2006	0		
11	227	10/23/2006	н		
"	228	10/23/2006	n		
"	256	10/23/2006	н		
ABOVE	SEARCH	10/23/2006	n		
UP-DAT.					
epda	Ae fle S	2/21/07			
		2/21/07	Scc		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		•			
			, .		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST, US-PGPUB,USPAT, EPO,JPO,DERWENT,IBM- TDB, SEE ATTACHED SEARCH HISTORY.	10/23/2006	scc		
382/187, 155,173,229,292.CCLS. 345/467.CCLS. 704/232,227,228,256.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	10/23/2006	n		
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.	10/23/2006	n		
INVENTOR NAME SEARCH.	10/23/2006	n		
IEEE OR INSPEC DATA BASE SEARCH .	10/23/2006	n		
ABOVE SEARCH UP DATE.	10/23/2006	n		